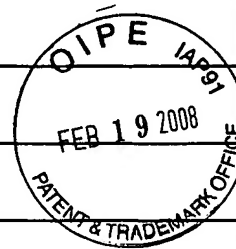


INFORMATION DISCLOSURE STATEMENT

FORM PTO 1449 (modified)

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY DOCKET NO.
2006_0745ASERIAL NO.
10/579,630LIST OF REFERENCES CITED BY APPLICANT(S)
(Use several sheets if necessary)APPLICANT
Ken-ichi KITAYAMA et al.

Date Submitted to PTO: February 19, 2008

FILING DATE
September 11, 2007GROUP
2627

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA	6,160,504	12-12-00	Fields et al.			
	AB						
	AG						
	AD						
	AE						
	AF						
	AG						
	AH						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
	BA	0 985 956	3-15-00	Europe			x
	BB	1 093 011	4-18-01	Europe			x
	BC	93/05592	3-18-93	WO			x

OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)

CA	Supplementary European Search Report issued January 11, 2008 in the European Application No. EP 04-81 8553.
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EXAMINER

DATE CONSIDERED

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.